CERTIFICATE OF ANALYSIS

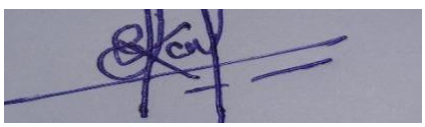
Product Name	Copper Oxide NanoParticle	**Manifaturing Date**	18-Nov-2024
Sample Qty	100g	**Analysis Date**	1-Dec-2024
Batch No	LAICD3887	**Referred Standard**	Sophisticated Analysis Kochin
CAS No	1317-38-0	**Material Type**	Nanomaterial

Test

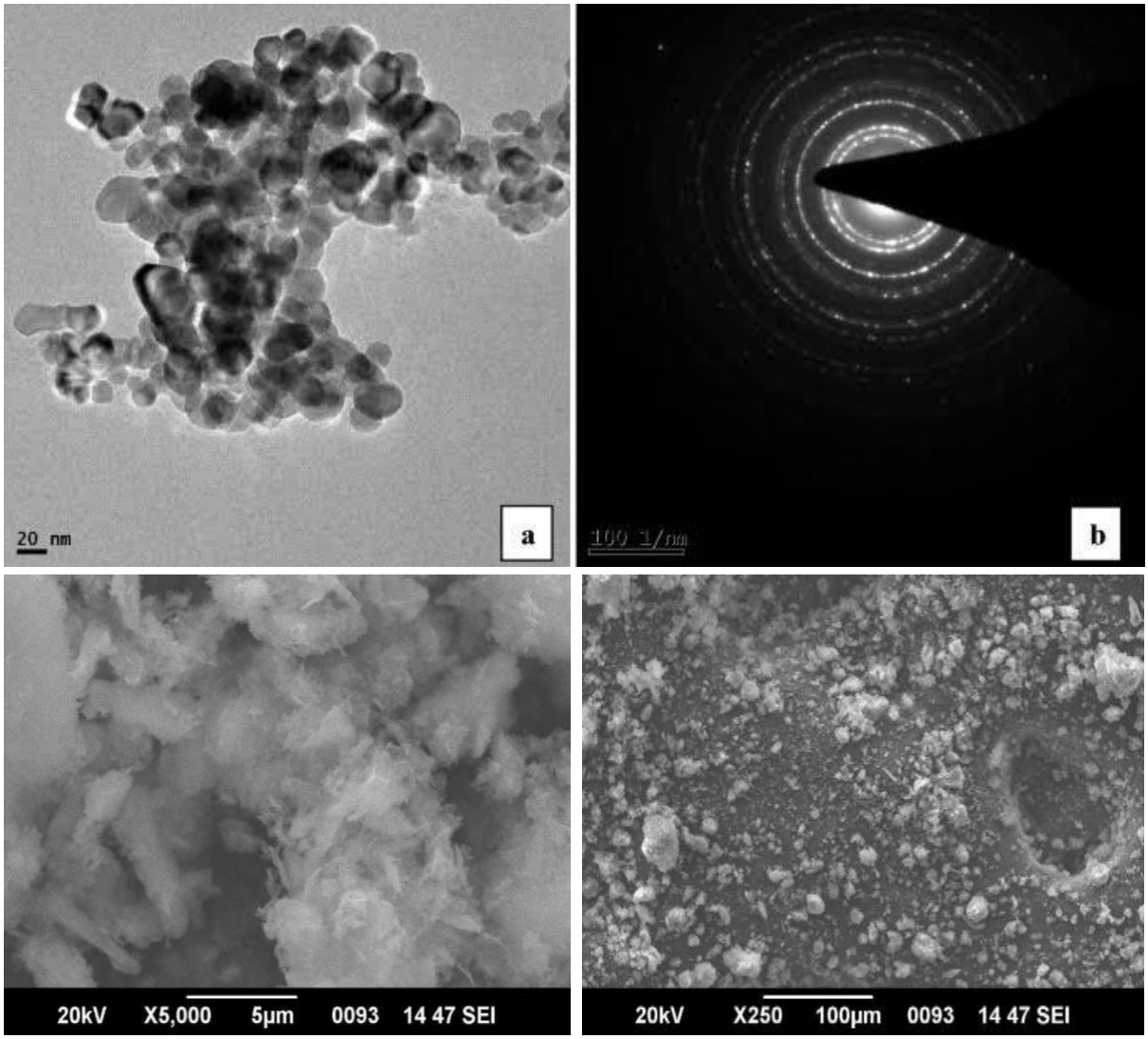
Test	**Specification**	**RESULT**
X-ray Diffraction	Size Measurement	16nm-25nm
SEM	Image of Particle	Spherical Rod
TEM	Particle Size	20nm
EDS	Nano Test	MgO Nanoparticle
Melting point	M.p	2800 oC
Appearance	Powder	Powder
Purity	HPLC	99%
Colour	Spectrophotometer	White

Head of Chemistry

Signature.



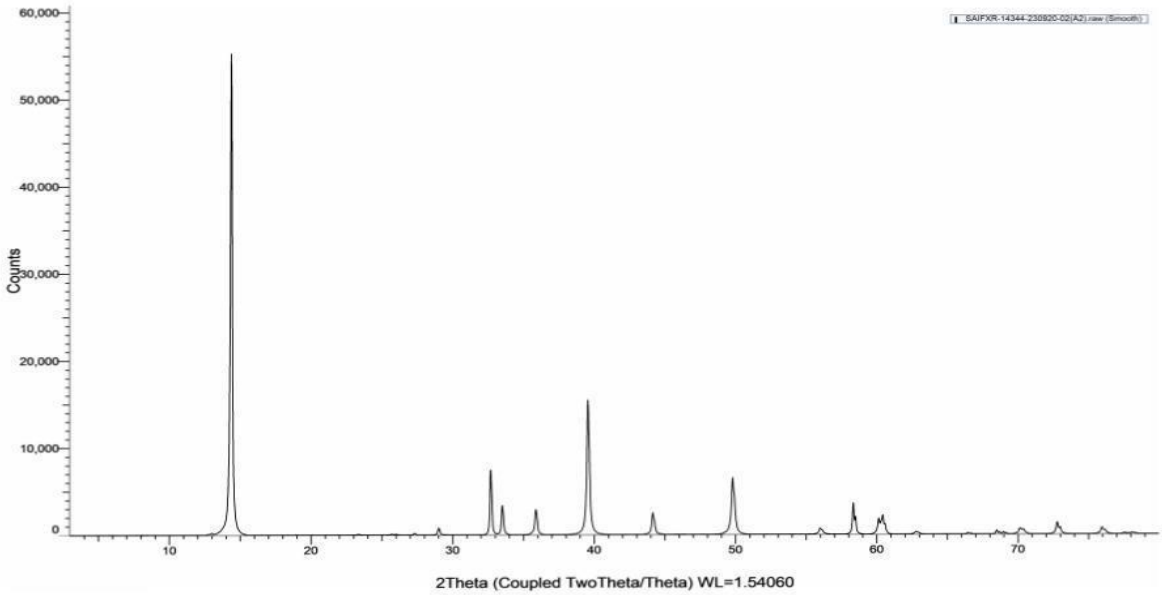
TEM &SEM


20 nm
a
b
20kV X5,000 5µm 0093 14 47 SEI
20kV X250 100µm 0093 14 47 SEI

XRD :-

X-Ray Diffractogram- SAIF Kochi

A2 (Coupled TwoTheta/Theta)



2Theta

Sample ID	A2
File Name	SAIFXR-14344-230920-02(A2).raw (Smooth)
Scan Type	Coupled TwoTheta/Theta
Scan Mode	Continuousscan
Start	3.000 °
End	79.999 °
Step Size	0.020 °
Total Time/Step	57.60 s
Temperature	25 °C (Room)
Goniometer Radius	200.5 mm
Sample Rotation	0.000 1/min
Anode	Cu
kα2 Ratio	0.50000
Wavelength for display	1.54060 Å
Generator kV	40.0 kV
Generator mA	35.0 mA
Detector Opening	2.945 °
Primary Soller slit	2.500 °
Secondary Soller slit	2.500 °
Air-Scatter Screen Mode	Automatic
Divergence Slit	15.000 mm
Antiscatter Slit	18.000
Slit Mode	Variable
Compute Crystallinity	No
%-Crystallinity	
%-Amorphous	
Global Area	